Search Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination
10/784,954	OIKAWA ET AL.
Examiner	Art Unit
Patrick H. Mackey	3651

	SEAR	CHED	
Class	Subclass	Date	Examiner
271	208		
270	58.08	9/30/2004	РНМ
Updated	Search	2/25/2005	PHM
Updated	Search	6/7/2005	PHM
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INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
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SEAR (INCLUDING SI	CH NOTES EARCH STRATEGY)
	DATE	EXMR
Text Search	9/30/2004	PHM
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